Product Change Notification: CAAN-27GELQ064

Date:

30-Jan-2025

Product Category:

Digital Temperature Sensors

Notification Subject:

CCB 7387 Initial Notice: Qualification of NSEB (UTL-2) as a new final test site for selected AT30TS74, AT30TS750A, AT30TS75A, AT30TSE004A, AT30TSE752A, AT30TSE754A and AT30TSE758A device families available in 8L MSOP (3x3mm), 8L SOIC (3.90mm) and 8L UDFN (2x3x0.6mm) packages.

Affected CPNs:

CAAN-27GELQ064_Affected_CPN_01302025.pdf
CAAN-27GELQ064_Affected_CPN_01302025.csv

PCN Status: Initial Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.
Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of NSEB (UTL-2) as a new final test site for selected AT30TS74, AT30TS750A, AT30TS75A, AT30TSE004A, AT30TSE752A, AT30TSE754A and AT30TSE758A device families available in 8L MSOP (3x3mm), 8L SOIC (3.90mm) and 8L UDFN (2x3x0.6mm) packages.

Pre and Post Summary Changes:

	Pre Change	**Post Change**
Final Test Site	UTAC Thai Limited (UTL-3) (UTL-3)	UTAC Thai Limited (UTL-2) (NSEB)
Packing Method	No change	

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance by qualifying NSEB (UTL-2) as a new final test site.

Change Implementation Status: In Progress

Estimated Qualification Completion Date: February 2025

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Timetable Summary:

	January 2025					**February 2025**			
Work Week	01	02	03	04	05	06	07	08	09
Initial PCN Issue Date					X				
Qual Report Availability							X		
Final PCN Issue Date							X		

Method to Identify Change: Traceability Code

Qualification Plan: Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History: January 30, 2025: Issued initial notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_CAAN-27GELQ064_Qual_Plan.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the **PCN FAQ** section.

If you wish to change your PCN profile, including opt out, please go to the **PCN home page** select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

AT30TSE758A-MA8M-T
AT30TSE758A-SS8M-B
AT30TSE758A-SS8M-T
AT30TSE758A-XM8M-B
AT30TSE758A-XM8M-T
AT30TS74-MA8M-T
AT30TS74-SS8M-B
AT30TS74-SS8M-T
AT30TS74-XM8M-B
AT30TS74-XM8M-T
AT30TS750A-MA8M-T
AT30TS750A-SS8M-B
AT30TS750A-SS8M-T
AT30TS750A-XM8M-B
AT30TS750A-XM8M-T
AT30TS75A-MA8M-T
AT30TS75A-SS8M-B
AT30TS75A-SS8M-T
AT30TS75A-XM8M-B
AT30TS75A-XM8M-T
AT30TSE004A-MA5M-T
AT30TSE752A-MA8M-T
AT30TSE752A-SS8M-B
AT30TSE752A-SS8M-T
AT30TSE752A-XM8M-B
AT30TSE752A-XM8M-T
AT30TSE754A-MA8M-T
AT30TSE754A-SS8M-B
AT30TSE754A-SS8M-T
AT30TSE754A-XM8M-B
AT30TSE754A-XM8M-T

QUALIFICATION PLAN SUMMARY

PCN#: CAAN-27GELQ064

Date:
January 17, 2025

Qualification of NSEB (UTL-2) as a new final test site for selected AT30TS74, AT30TS750A, AT30TS75A, AT30TSE004A, AT30TSE752A, AT30TSE754A and AT30TSE758A device families available in 8L MSOP (3x3mm), 8L SOIC (3.90mm) and 8L UDFN (2x3x0.6mm) packages.

Purpose: **Qualification of NSEB (UTL-2) as a new final test site for selected AT30TS74, AT30TS750A, AT30TS75A, AT30TSE004A, AT30TSE752A, AT30TSE754A and AT30TSE758A device families available in 8L MSOP (3x3mm), 8L SOIC (3.90mm) and 8L UDFN (2x3x0.6mm) packages.**

CCB No.: **7387**

Test / Evaluation	Test Conditions / Parameters	Sample Size	Qty of Lots	Fail/Accept Criteria
Bin and Yield Comparison	Test the same units at existing and destination locations and compare BIN and Yield data.	3000	1	≤0.1%
Parametric / Characterization Comparison	Characterize the same units at existing and destination locations and compare data.	33	1	≤10%
Correlation Lot Report	Yield at each step and reject analysis between systems. 33 units are tested as lot correlation. Accept on yield match within 0.1%	33	1	≤0.1%